

CDCE(L)925: Flexible Low Power LVCMOS Clock Generator

With SSC Support for EMI Reduction

1 Features

- Member of programmable clock generator family
 - CDCEx913: 1PLL, 3 Outputs
 - CDCEx925: 2PLL, 5 Outputs
 - CDCEx925: 3PLL, 7 Outputs
 - CDCEx949: 4PLL, 9 Outputs
- In-system programmability and EEPROM
 - Serial programmable volatile register
 - Nonvolatile EEPROM to store customer settings
- Flexible input clocking concept
 - External crystal: 8MHz to 32MHz
 - On-chip VCXO: pull range ± 150 ppm
 - Single-ended LVCMOS up to 160MHz
- Free selectable output frequency up to 230MHz
- Low-noise PLL core
 - PLL loop filter components integrated
 - Low period jitter (typical 60ps)
- Separate output supply pins
 - CDCE925: 3.3V and 2.5V
 - CDCEL925: 1.8V
- Flexible clock driver
 - Three user-definable control inputs [S0/S1/S2], for example, SSC selection, frequency switching, output enable, or power down
 - Generates highly accurate clocks for video, audio, USB, IEEE1394, RFID, Bluetooth®, WLAN, Ethernet™, and GPS
 - Generates common clock frequencies used with TI DaVinci™, OMAP™, DSPs
 - Programmable SSC modulation
 - Enables 0PPM clock generation
- 1.8V device power supply
- Wide temperature range: -40°C to 85°C
- Packaged in TSSOP
- Development and programming kit for easy PLL design and programming TI (Pro-Clock™)

2 Applications

- D-TVs
- STBs
- IP-STBs
- DVD players
- DVD recorders
- Printers

3 Description

The CDCE925 and CDCEL925 are modular PLL-based low-cost, high-performance, programmable clock synthesizers, multipliers, and dividers. CDCE925 and CDCEL925 generate up to five output clocks from a single input frequency. Each output can be programmed in-system for any clock frequency up to 230MHz, using up to two independent configurable PLLs.

The CDCEx925 has a separate output supply pin, V_{DDOUT} , which is 1.8V for CDCEL925 and 2.5V to 3.3V for CDCE925.

The input accepts an external crystal or LVCMOS clock signal. In case of a crystal input, an on-chip load capacitor is adequate for most applications. The value of the load capacitor is programmable from 0 to 20pF. Additionally, an on-chip VCXO is selectable which allows synchronization of the output frequency to an external control signal, that is, PWM signal.

The deep M/N divider ratio allows the generation of zero-ppm audio/video, networking (WLAN, Bluetooth, Ethernet, GPS), or interface (USB, IEEE1394, memory stick) clocks from a 27MHz reference input frequency, for example.

All PLLs support SSC (spread-spectrum clocking). SSC can be center-spread or down-spread clocking, which is a common technique to reduce electromagnetic interference (EMI).

Based on the PLL frequency and the divider settings, the internal loop filter components are automatically adjusted to achieve high stability and optimized jitter transfer characteristic of each PLL.



The device supports nonvolatile EEPROM programming for easy customization of the device in the application. It is preset to a factory default configuration and can be reprogrammed to a different application configuration before it goes onto the PCB or reprogrammed by in-system programming. All device settings are programmable through the SDA/SCL bus, a 2-wire serial interface.

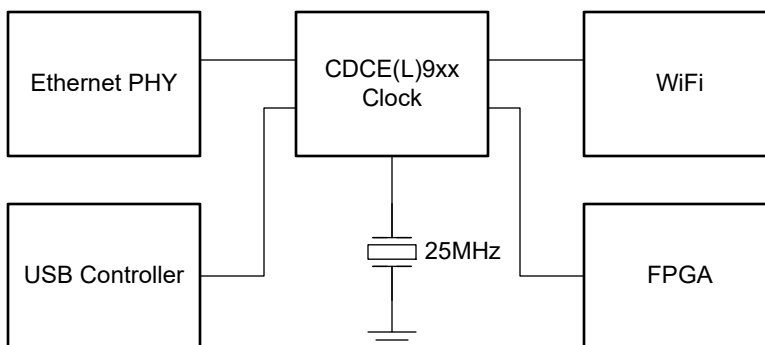
Three, free programmable control inputs, S0, S1, and S2, can be used to select different frequencies, or change the SSC setting for lowering EMI, or other control features like outputs disable to low, outputs in high-impedance state, power down, PLL bypass, and so forth.

The CDCx925 operates in a 1.8V environment and in a temperature range of –40°C to 85°C.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾
CDCEx925	PW (TSSOP, 16)	5.00mm × 4.40mm

- (1) For all available packages, see [Section 12](#).
- (2) The package size (length × width) is a nominal value and includes pins, where applicable.



Typical Application Schematic

Table of Contents

1 Features	1	7.5 Programming.....	16
2 Applications	1	8 Register Maps	18
3 Description	1	8.1 SDA/SCL Configuration Registers.....	18
4 Pin Configuration and Functions	4	9 Application and Implementation	23
5 Specifications	5	9.1 Application Information.....	23
5.1 Absolute Maximum Ratings.....	5	9.2 Typical Application.....	23
5.2 ESD Ratings.....	5	9.3 Power Supply Recommendations.....	27
5.3 Recommended Operating Conditions.....	5	9.4 Layout.....	27
5.4 Thermal Information.....	6	10 Device and Documentation Support	29
5.5 Electrical Characteristics.....	6	10.1 Device Support.....	29
5.6 EEPROM Specification.....	8	10.2 Documentation Support.....	29
5.7 Timing Requirements: CLK_IN.....	8	10.3 Receiving Notification of Documentation Updates.....	29
5.8 Timing Requirements: SDA/SCL.....	8	10.4 Support Resources.....	29
5.9 Typical Characteristics.....	9	10.5 Trademarks.....	29
6 Parameter Measurement Information	10	10.6 Electrostatic Discharge Caution.....	29
7 Detailed Description	11	10.7 Glossary.....	29
7.1 Overview.....	11	11 Revision History	30
7.2 Functional Block Diagram.....	12	12 Mechanical, Packaging, and Orderable Information	30
7.3 Feature Description.....	12		
7.4 Device Functional Modes.....	15		

4 Pin Configuration and Functions

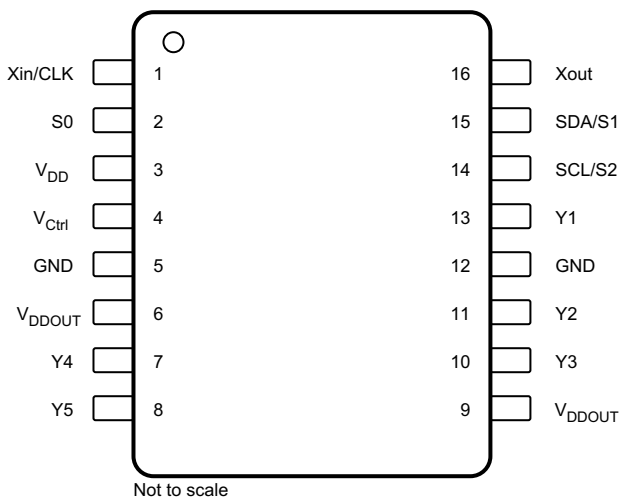


Figure 4-1. PW Package 16-Pin TSSOP Top View

Table 4-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.		
GND	5, 12	G	Ground
SCL/S2	14	I	SCL: Serial clock input (default configuration), LVCMOS; internal pullup S2: User-programmable control input; LVCMOS inputs; internal pullup
SDA/S1	15	I/O	SDA: Bidirectional serial data input/output (default configuration), LVCMOS; internal pullup S1: User-programmable control input; LVCMOS inputs; internal pullup
S0	2	I	User-programmable control input S0; LVCMOS inputs; internal pullup
V _{Ctrl}	4	I	VCXO control voltage (leave open or pull up when not used)
V _{DD}	3	P	1.8-V power supply for the device
V _{DDOUT}	6, 9	P	CDCEL925: 1.8-V supply for all outputs
			CDCE925: 3.3-V or 2.5-V supply for all outputs
Xin/CLK	1	I	Crystal oscillator input or LVCMOS clock Input (selectable through SDA/SCL bus)
Xout	16	O	Crystal oscillator output (leave open or pull up when not used)
Y1	13	O	LVCMOS output
Y2	11		
Y3	10		
Y4	7		
Y5	8		

(1) G = Ground, I = Input, O = Output, P = Power

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

	MIN	MAX	UNIT
Supply voltage, V_{DD}	-0.5	2.5	V
Input voltage, V_I ^{(2) (3)}	-0.5	$V_{DD} + 0.5$	V
Output voltage, V_O ⁽²⁾	-0.5	$V_{DD} + 0.5$	V
Input current, I_I ($V_I < 0$, $V_I > V_{DD}$)		20	mA
Continuous output current, I_O		50	mA
Maximum junction temperature, T_J		125	°C
Storage temperature, T_{stg}	-65	150	°C

- (1) Operation outside the *Absolute Maximum Ratings* may cause permanent device damage. *Absolute Maximum Ratings* do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Conditions*. If used outside the *Recommended Operating Conditions* but within the *Absolute Maximum Ratings*, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) The input and output negative voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- (3) SDA and SCL can go up to 3.6V as stated in the *Recommended Operating Conditions* table.

5.2 ESD Ratings

		VALUE	UNIT
$V_{(ESD)}$ Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V
	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1500	

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT
V_{DD}	Device supply voltage	1.7	1.8	1.9	V
V_{DDOUT}	Output Yx supply voltage	CDCE925		3.6	V
		CDCEL925	1.7	1.9	
V_{IL}	Low-level input voltage LVC MOS			$0.3 \times V_{DD}$	V
V_{IH}	High-level input voltage LVC MOS	$0.7 \times V_{DD}$			V
$V_{I(thresh)}$	Input voltage threshold LVC MOS		$0.5 \times V_{DD}$		V
$V_{I(S)}$	Input voltage	S0	0	1.9	V
		S1, S2, SDA, SCL; $V_{I(thresh)} = 0.5V_{DD}$	0	3.6	
$V_{I(CLK)}$	Input voltage, CLK	0		1.9	V
I_{OH} / I_{OL}	Output current	$V_{DDOUT} = 3.3V$		±12	mA
		$V_{DDOUT} = 2.5V$		±10	
		$V_{DDOUT} = 1.8V$		±8	
C_L	Output load LVC MOS			15	pF
T_A	Operating free-air temperature	-40		85	°C
CRYSTAL AND VCXO ⁽¹⁾					
f_{Xtal}	Crystal input frequency (fundamental mode)	8	27	32	MHz
ESR	Effective series resistance			100	Ω
f_{PR}	Pulling ($0V \leq V_{Ctrl} \leq 1.8V$) ⁽²⁾	±120	±150		ppm
V_{Ctrl}	Frequency control voltage	0		V_{DD}	V
C_0/C_1	Pullability ratio			220	
C_L	On-chip load capacitance at Xin and Xout	0		20	pF

- (1) For more information about VCXO configuration, and crystal recommendation, see the [VCXO Application Guideline for CDCE\(L\)9xx Family application note](#).

- (2) Pulling range depends on crystal-type, on-chip crystal load capacitance and PCB stray capacitance; pulling range of minimum ± 120 ppm applies for crystal listed in the [VCXO Application Guideline for CDCE\(L\)9xx Family application note](#).

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		CDCEx925	UNIT	
		PW (TSSOP)		
		20 PINS		
R _{θJA}	Junction-to-ambient thermal resistance	Airflow 0 (LFM)	101	°C/W
		Airflow 150 (LFM)	85	
		Airflow 200 (LFM)	84	
		Airflow 250 (LFM)	82	
		Airflow 500 (LFM)	74	
R _{θJC(top)}	Junction-to-case (top) thermal resistance	42	°C/W	
R _{θJB}	Junction-to-board thermal resistance	63.63	°C/W	
ψ _{JT}	Junction-to-top characterization parameter	1.01	°C/W	
ψ _{JB}	Junction-to-board characterization parameter	58.12	°C/W	
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	58	°C/W	

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
I _{DD}	Supply current (see Figure 5-1)	All outputs off, f _{CLK} = 27MHz, f _{VCO} = 135MHz, f _{OUT} = 27MHz	All PLLS on	20		mA
			Per PLL	9		
I _{DDOUT}	Supply current (see Figure 5-2 and Figure 5-3)	No load, all outputs on, f _{OUT} = 27MHz	CDCE925, V _{DDOUT} = 3.3V	2		mA
			CDCEL925, V _{DDOUT} = 1.8V	1		
I _{DDPD}	Power-down current. Every circuit powered down except SDA/SCL	f _{IN} = 0MHz, V _{DD} = 1.9V		30		μA
V _{PUC}	Supply voltage V _{DD} threshold for power-up control circuit		0.85		1.45	V
f _{VCO}	VCO frequency range of PLL		80		230	MHz
f _{OUT}	LVC MOS output frequency	CDCEx925 V _{DDOUT} = 1.8V	230			MHz
LVC MOS						
V _{IK}	LVC MOS input voltage	V _{DD} = 1.7V, I _S = -18mA			-1.2	V
I _I	LVC MOS input current	V _I = 0V or V _{DD} , V _{DD} = 1.9V			±5	μA
I _{IH}	LVC MOS input current for S0/S1/S2	V _I = V _{DD} , V _{DD} = 1.9V			5	μA
I _{IL}	LVC MOS Input current for S0/S1/S2	V _I = 0V, V _{DD} = 1.9V			-4	μA
C _I	Input capacitance at Xin/Clk	V _{Clk} = 0V or V _{DD}		6		pF
	Input capacitance at Xout	V _{Xout} = 0V or V _{DD}		2		
	Input capacitance at S0/S1/S2	V _{IS} = 0V or V _{DD}		3		
CDCE925 – LVC MOS FOR V_{DDOUT} = 3.3V						
V _{OH}	LVC MOS high-level output voltage	V _{DDOUT} = 3V, I _{OH} = -0.1mA	2.9			V
		V _{DDOUT} = 3V, I _{OH} = -8mA	2.4			
		V _{DDOUT} = 3V, I _{OH} = -12mA	2.2			
V _{OL}	LVC MOS low-level output voltage	V _{DDOUT} = 3V, I _{OL} = 0.1mA			0.1	V
		V _{DDOUT} = 3V, I _{OL} = 8mA			0.5	
		V _{DDOUT} = 3V, I _{OL} = 12mA			0.8	
t _{PLH} , t _{PHL}	Propagation delay	All PLL bypass		3.2		ns
t _r /t _f	Rise and fall time	V _{DDOUT} = 3.3V (20%–80%)		0.6		ns

5.5 Electrical Characteristics (continued)

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{jitter(cc)}	Cycle-to-cycle jitter ^{(2) (3)}	1PLL switching, Y2-to-Y3		50	70	ps
		2PLL switching, Y2-to-Y5		90	130	
t _{jitter(per)}	Peak-to-peak period jitter ⁽³⁾	1PLL switching, Y2-to-Y3		60	100	ps
		2PLL switching, Y2-to-Y5		100	160	
t _{sk(o)}	Output skew ⁽⁴⁾	f _{OUT} = 50MHz, Y1-to-Y3			70	ps
		f _{OUT} = 50MHz, Y2-to-Y5			150	
odc	Output duty cycle ⁽⁵⁾	f _{VCO} = 100MHz, Pdiv = 1	45%		55%	
CDCE925 – LVCMOS FOR V_{DDOUT} = 2.5V						
V _{OH}	LVCMOS high-level output voltage	V _{DDOUT} = 2.3V, I _{OH} = -0.1mA	2.2			V
		V _{DDOUT} = 2.3V, I _{OH} = -6mA	1.7			
		V _{DDOUT} = 2.3V, I _{OH} = -10mA	1.6			
V _{OL}	LVCMOS low-level output voltage	V _{DDOUT} = 2.3V, I _{OL} = 0.1mA			0.1	V
		V _{DDOUT} = 2.3V, I _{OL} = 6mA			0.5	
		V _{DDOUT} = 2.3V, I _{OL} = 10mA			0.7	
t _{PLH} , t _{PHL}	Propagation delay	All PLL bypass		3.6		ns
t _r /t _f	Rise and fall time	V _{DDOUT} = 2.5V (20%–80%)		0.8		ns
t _{jitter(cc)}	Cycle-to-cycle jitter ^{(2) (3)}	1PLL switching, Y2-to-Y3		50	70	ps
		2PLL switching, Y2-to-Y5		90	130	
t _{jitter(per)}	Peak-to-peak period jitter ⁽³⁾	1PLL switching, Y2-to-Y3		60	100	ps
		2PLL switching, Y2-to-Y5		100	160	
t _{sk(o)}	Output skew ⁽⁴⁾	f _{OUT} = 50MHz, Y1-to-Y3			70	ps
		f _{OUT} = 50MHz, Y2-to-Y5			150	
odc	Output duty cycle ⁽⁵⁾	f _{VCO} = 100MHz, Pdiv = 1	45%		55%	
CDCEL925 – LVCMOS FOR V_{DDOUT} = 1.8V						
V _{OH}	LVCMOS high-level output voltage	V _{DDOUT} = 1.7V, I _{OH} = -0.1mA	1.6			V
		V _{DDOUT} = 1.7V, I _{OH} = -4mA	1.4			
		V _{DDOUT} = 1.7V, I _{OH} = -8mA	1.1			
V _{OL}	LVCMOS low-level output voltage	V _{DDOUT} = 1.7V, I _{OL} = 0.1mA			0.1	V
		V _{DDOUT} = 1.7V, I _{OL} = 4mA			0.3	
		V _{DDOUT} = 1.7V, I _{OL} = 8mA			0.6	
t _{PLH} , t _{PHL}	Propagation delay	All PLL bypass		2.6		ns
t _r /t _f	Rise and fall time	V _{DDOUT} = 1.8V (20%–80%)		0.7		ns
t _{jitter(cc)}	Cycle-to-cycle jitter ^{(2) (3)}	1PLL switching, Y2-to-Y3		80	110	ps
		2PLL switching, Y2-to-Y5		130	200	
t _{jitter(per)}	Peak-to-peak period jitter ⁽³⁾	1PLL switching, Y2-to-Y3		100	130	ps
		2PLL switching, Y2-to-Y5		150	220	
t _{sk(o)}	Output skew ⁽⁴⁾	f _{OUT} = 50MHz, Y1-to-Y3			50	ps
		f _{OUT} = 50MHz, Y2-to-Y5			110	
odc	Output duty cycle ⁽⁵⁾	f _{VCO} = 100MHz, Pdiv = 1	45%		55%	
SDA AND SCL						
V _{IK}	SCL and SDA input clamp voltage	V _{DD} = 1.7V, I _I = -18mA			-1.2	V
I _{IH}	SCL and SDA input current	V _I = V _{DD} , V _{DD} = 1.9V			±10	µA
V _{IH}	SDA/SCL input high voltage ⁽⁶⁾		0.7 × V _{DD}			V
V _{IL}	SDA/SCL input low voltage ⁽⁶⁾			0.3 × V _{DD}		V
V _{OL}	SDA low-level output voltage	I _{OL} = 3mA, V _{DD} = 1.7V			0.2 × V _{DD}	V
C _I	SCL/SDA Input capacitance	V _I = 0V or V _{DD}		3	10	pF

(1) All typical values are at respective nominal V_{DD}.

(2) 10,000 cycles

- (3) Jitter depends on configuration. Jitter data is for input frequency = 27MHz, $f_{VCO} = 135\text{MHz}$, $f_{OUT} = 27\text{MHz}$. $f_{OUT} = 3.072\text{MHz}$ or input frequency = 27MHz, $f_{VCO} = 108\text{MHz}$, $f_{OUT} = 27\text{MHz}$. $f_{OUT} = 16.384\text{MHz}$, $f_{OUT} = 25\text{MHz}$, $f_{OUT} = 74.25\text{MHz}$, $f_{OUT} = 48\text{MHz}$
- (4) The tsk(o) specification is only valid for equal loading of each bank of outputs, and the outputs are generated from the same divider, data sampled on rising edge (t_r).
- (5) odc depends on output rise- and fall-time (t_r/t_f);
- (6) SDA and SCL pins are 3.3V tolerant.

5.6 EEPROM Specification

		MIN	TYP	MAX	UNIT
EEcyc	Programming cycles of EEPROM	100	1000		cycles
EEret	Data retention	10			years

5.7 Timing Requirements: CLK_IN

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
f_{CLK}	LVCMOS clock input frequency	PLL bypass mode		160	MHz
		PLL mode	8	160	
t_r / t_f	Rise and fall time CLK signal (20% to 80%)			3	ns
duty _{CLK}	Duty cycle CLK at $V_{DD} / 2$	40%		60%	

5.8 Timing Requirements: SDA/SCL

over operating free-air temperature range (unless otherwise noted; see [Figure 7-3](#))

		MIN	NOM	MAX	UNIT
f_{SCL}	SCL clock frequency	Standard mode		100	kHz
		Fast mode	0	400	
$t_{su}(START)$	START setup time (SCL high before SDA low)	Standard mode	4.7		μs
		Fast mode	0.6		
$t_h(START)$	START hold time (SCL low after SDA low)	Standard mode	4		μs
		Fast mode	0.6		
$t_w(SCLL)$	SCL low-pulse duration	Standard mode	4.7		μs
		Fast mode	1.3		
$t_w(SCLH)$	SCL high-pulse duration	Standard mode	4		μs
		Fast mode	0.6		
$t_h(SDA)$	SDA hold time (SDA valid after SCL low)	Standard mode	0	3.45	μs
		Fast mode	0	0.9	
$t_{su}(SDA)$	SDA setup time	Standard mode	250		ns
		Fast mode	100		
t_r	SCL/SDA input rise time	Standard mode		1000	ns
		Fast mode		300	
t_f	SCL/SDA input fall time, standard and fast mode			300	ns
$t_{su}(STOP)$	STOP setup time	Standard mode	4		μs
		Fast mode	0.6		
t_{BUS}	Bus free time between a STOP and START condition	Standard mode	4.7		μs
		Fast mode	1.3		

5.9 Typical Characteristics

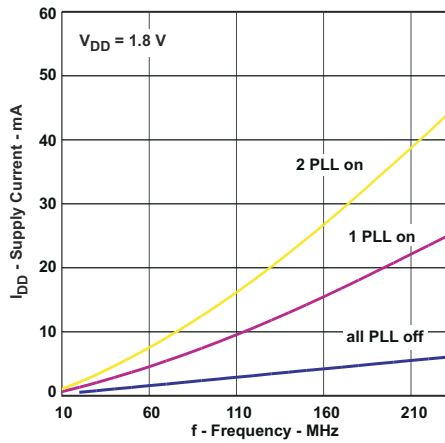


Figure 5-1. CDCE925 Supply Current vs PLL Frequency

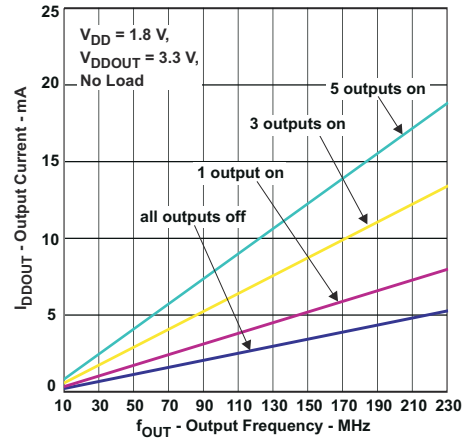


Figure 5-2. CDCE925 Output Current vs Output Frequency

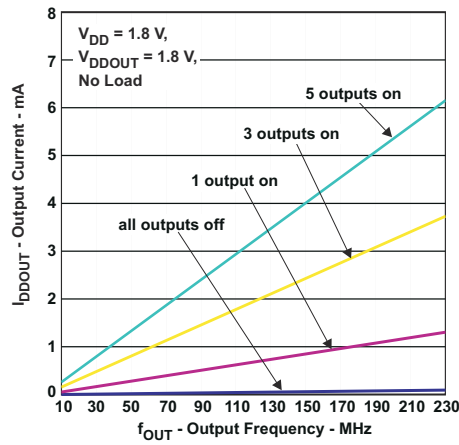


Figure 5-3. CDCEL925 Output Current vs Output Frequency

6 Parameter Measurement Information

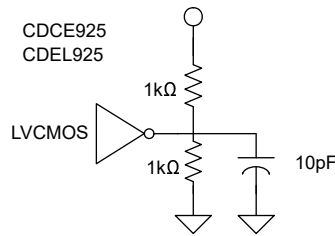


Figure 6-1. Test Load

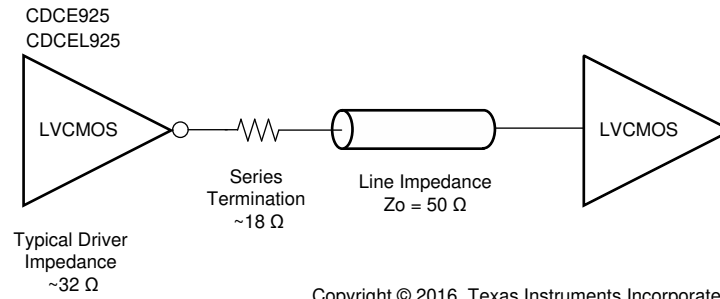


Figure 6-2. Test Load for 50Ω Board Environment

7 Detailed Description

7.1 Overview

The CDCE925 and CDCEL925 devices are modular PLL-based, low-cost, high-performance, programmable clock synthesizers, multipliers, and dividers. They generate up to five output clocks from a single input frequency. Each output can be programmed in-system for any clock frequency up to 230MHz, using one of the two integrated configurable PLLs.

The CDCx925 has separate output supply pins, V_{DDOUT} , which is 1.8V for CDCEL925 and 2.5V to 3.3V for CDCE925.

The input accepts an external crystal or LVCMOS clock signal. If an external crystal is used, an on-chip load capacitor is adequate for most applications. The value of the load capacitor is programmable from 0pF to 20pF. Additionally, a selectable on-chip VCXO allows synchronization of the output frequency to an external control signal, that is, the PWM signal.

The deep M/N divider ratio allows the generation of 0ppm audio and video, networking (WLAN, Bluetooth, Ethernet, GPS), or interface (USB, IEEE1394, memory stick) clocks from a reference input frequency such as 27MHz.

All PLLs support spread-spectrum clocking (SSC). SSC can be center-spread or down-spread clocking. This is a common technique to reduce electro-magnetic interference (EMI).

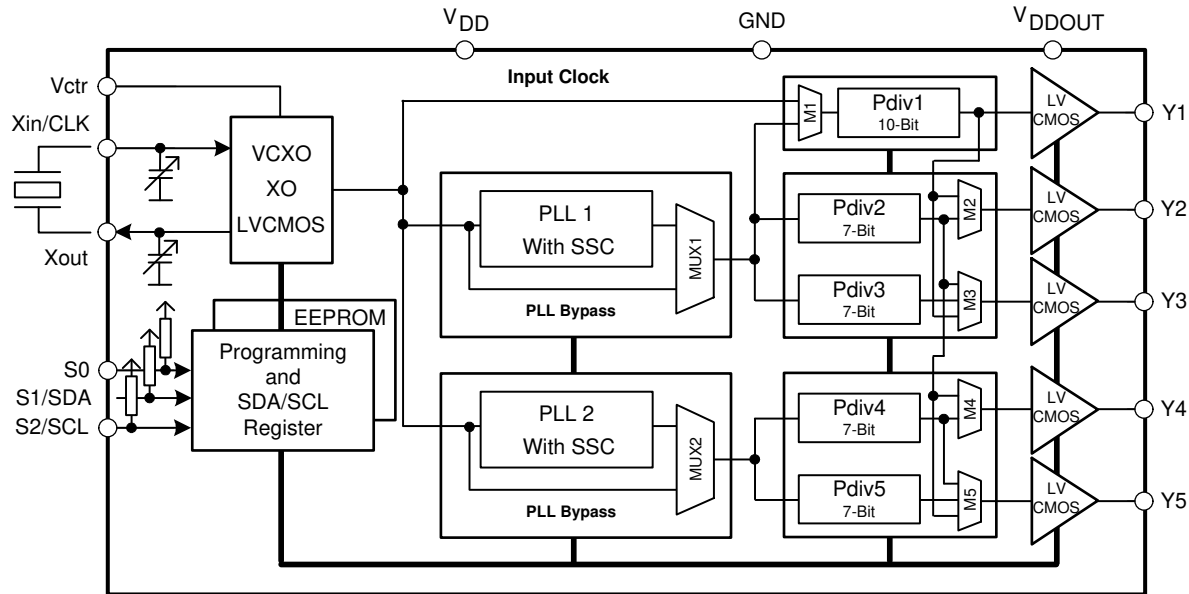
Based on the PLL frequency and the divider settings, the internal loop filter components are automatically adjusted to achieve high stability, and to optimize the jitter-transfer characteristic of each PLL.

The device supports non-volatile EEPROM programming for easy customization of the device in the application. It is preset to a factory default configuration (see [Default Device Setting](#)). The device can be reprogrammed to a different application configuration before PCB assembly, or reprogrammed by in-system programming. All device settings are programmable through the SDA and SCL bus, a 2-wire serial interface.

Three free programmable control inputs, S0, S1, and S2, can be used to control various aspects of operation including frequency selection, changing the SSC parameters to reduce EMI, PLL bypass, power down, or other control features like outputs disable to low, outputs in high-impedance state, and so forth.

The CDCx925 operates in a 1.8V environment within a temperature range of -40°C to 85°C .

7.2 Functional Block Diagram



Copyright © 2016, Texas Instruments Incorporated

Figure 7-1. Functional Block Diagram for CDCE925

7.3 Feature Description

7.3.1 Control Terminal Setting

The CDCE925 has three user-definable control terminals (S0, S1, and S2) which allow external control of device settings. The terminals can be programmed to any of the following settings:

- Spread spectrum clocking selection → spread type and spread amount selection
- Frequency selection → switching between any of two user-defined frequencies
- Output state selection → output configuration and power-down control

The user can predefine up to eight different control settings. [Table 7-1](#) and [Table 7-2](#) explain these settings.

Table 7-1. Control Terminal Definition

EXTERNAL CONTROL BITS	PLL1 SETTING			PLL2 SETTING			Y1 SETTING
	PLL frequency selection	SSC selection	Output Y2/Y3 selection	PLL frequency selection	SSC selection	Output Y4/Y5 selection	Output Y1 and power-down selection
Control function							

Table 7-2. PLL Setting (Can Be Selected for Each PLL Individual)

SSC SELECTION (CENTER/DOWN) ⁽¹⁾				
SSCx [3-Bits]			CENTER	DOWN
0	0	0	0% (off)	0% (off)
0	0	1	±0.25%	-0.25%
0	1	0	±0.5%	-0.5%
0	1	1	±0.75%	-0.75%
1	0	0	±1%	-1.0%
1	0	1	±1.25%	-1.25%
1	1	0	±1.5%	-1.5%
1	1	1	±2%	-2%
FREQUENCY SELECTION ⁽²⁾				

Table 7-2. PLL Setting (Can Be Selected for Each PLL Individual) (continued)

SSC SELECTION (CENTER/DOWN) ⁽¹⁾		
SSCx [3-Bits]	CENTER	DOWN
FSx	FUNCTION	
0	Frequency0	
1	Frequency1	
OUTPUT SELECTION ⁽³⁾ (Y2 ... Y5)		
YxYx	FUNCTION	
0	State0	
1	State1	

- (1) Center/down-spread, Frequency0/1 and State0/1 are user-definable in the PLLx configuration register.
- (2) Frequency0 and Frequency1 can be any frequency within the specified f_{VCO} range.
- (3) State0/1 selection is valid for both outputs of the corresponding PLL module and can be power down, high-impedance state, low, or active

Table 7-3. Y1 Setting

Y1 SELECTION ⁽¹⁾	
Y1	FUNCTION
0	State 0
1	State 1

- (1) State0 and State1 are user definable in the generic configuration register and can be power down, high-impedance state, low, or active.

SDA/S1 and SCL/S2 pins of the CDCE925 are dual-function pins. In the default configuration, they are predefined as the SDA/SCL serial programming interface. They can be programmed to control pins (S1/S2) by setting the relevant bits in the EEPROM. The changes of the bits in the control register (bit [6] of byte 02h) have no effect until they are written into the EEPROM.

When they are set as control pins, the serial programming interface is no longer available. However, if V_{DDOUT} is forced to GND, the two control pins, S1 and S2, temporarily act as serial programming pins (SDA/SCL).

S0 is not a multi-use pin; it is a control pin only.

7.3.2 Default Device Setting

The internal EEPROM of CDCE925 is preconfigured as shown in [Figure 7-2](#). The input frequency is passed through the output as a default. This allows the device to operate in default mode without the extra production step of programming it. The default setting appears after power is supplied or after a power-down/up sequence until it is reprogrammed by the user to a different application configuration. A new register setting is programmed through the serial SDA/SCL interface.

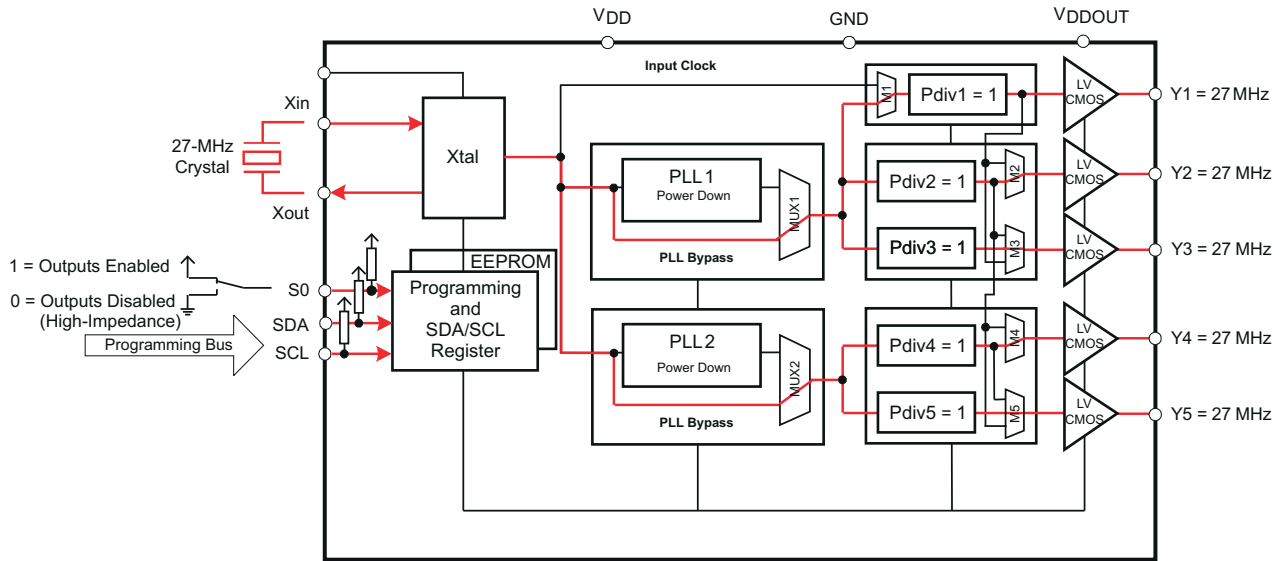


Figure 7-2. Preconfiguration of CDCE925 Internal EEPROM

Table 7-4 shows the factory default setting for the control terminal register (external control pins). While eight different register settings are possible, in default configuration, only the first two settings (0 and 1) can be selected with S0, as S1 and S2 are configured as programming pins in the default mode.

Table 7-4. Factory Default Settings for Control Terminal Register

(1)	EXTERNAL CONTROL PINS			Y1	PLL1 SETTINGS			PLL2 SETTINGS		
	S2	S1	S0	OUTPUT SELECTION	FREQUENCY SELECTION	SSC SELECTION	OUTPUT SELECTION	FREQUENCY SELECTION	SSC SELECTION	OUTPUT SELECTION
	SCL (I2C)	SDA (I2C)	0	High-impedance state	f_{VCO1_0}	Off	High-impedance state	f_{VCO2_0}	Off	High-impedance state
	SCL (I2C)	SDA (I2C)	1	Enabled	f_{VCO1_0}	Off	Enabled	f_{VCO2_0}	Off	Enabled

(1) S1 is SDA and S2 is SCL in default mode or when programmed (SPICON bit 6 of register 2 set to 0). They do not have any control-pin function but they are internally interpreted as if S1 = 0 and S2 = 0. S0, however, is a control pin which in the default mode switches all outputs ON or OFF (as previously predefined).

7.3.3 SDA/SCL Serial Interface

This section describes the SDA/SCL interface of the CDCE925 device. The CDCE925 operates as a slave device of the 2-wire serial SDA/SCL bus, compatible with the popular SMBus or I2C specification. It operates in the standard-mode transfer (up to 100kbps) and fast-mode transfer (up to 400kbps) and supports 7-bit addressing.

The SDA/S1 and SCL/S2 pins of the CDCE925 are dual-function pins. In the default configuration they are used as SDA/SCL serial programming interface. They can be reprogrammed as general-purpose control pins, S1 and S2, by changing the corresponding EEPROM setting, byte 02h, bit [6].

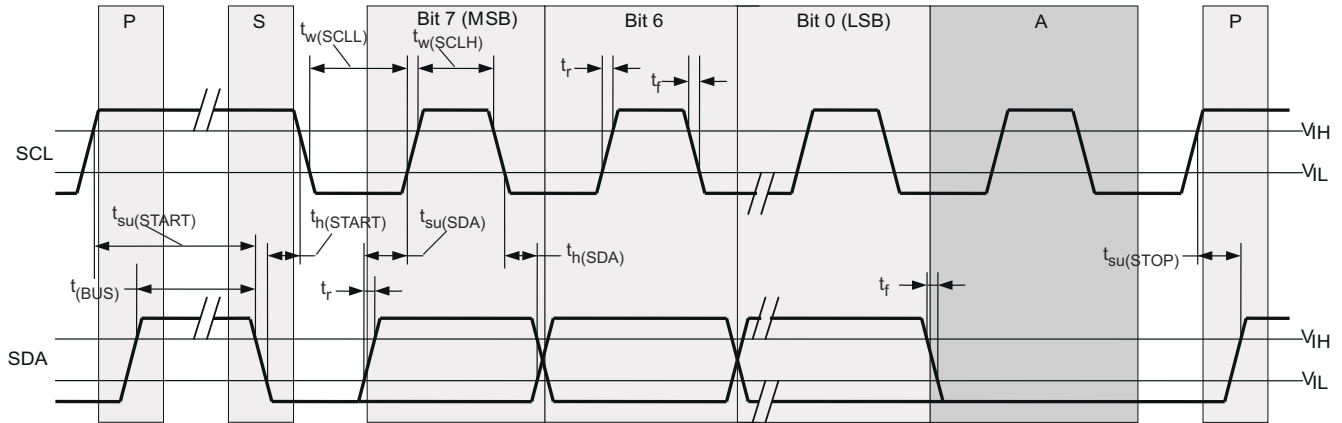


Figure 7-3. Timing Diagram for SDA/SCL Serial Control Interface

7.3.4 Data Protocol

The device supports *Byte Write and Byte Read* and *Block Write and Block Read* operations.

For *Byte Write/Read* operations, the system controller can individually access addressed bytes.

For *Block Write/Read* operations, the bytes are accessed in sequential order from lowest to highest byte (with most-significant bit first) with the ability to stop after any complete byte has been transferred. The numbers of bytes read out are defined by byte count in the generic configuration register. At the *Block Read* instruction, all bytes defined in the byte count must be read out to finish the read cycle correctly.

When a byte has been sent, it is written into the internal register and is effective immediately. This applies to each transferred byte regardless of whether this is a *Byte Write* or a *Block Write* sequence.

If the EEPROM write cycle is initiated, the internal SDA registers are written into the EEPROM. During this write cycle, data is not accepted at the SDA/SCL bus until the write cycle is completed. However, data can be read out during the programming sequence (*Byte Read* or *Block Read*). The programming status can be monitored by *EEPIP*, byte 01h–bit 6. Before beginning EEPROM programming, pull CLKIN LOW. CLKIN must be held LOW for the duration of EEPROM programming. After initiating EEPROM programming with *EEWRITE*, byte 06h-bit 0, do not write to the device registers until *EEPIP* is read back as a 0.

The offset of the indexed byte is encoded in the command code, as described in [Table 7-5](#).

Table 7-5. Slave Receiver Address (7 Bits)

DEVICE	A6	A5	A4	A3	A2	A1 ⁽¹⁾	A0 ⁽¹⁾	R/ W
CDCEx913	1	1	0	0	1	0	1	1/0
CDCEx925	1	1	0	0	1	0	0	1/0
CDCEx925	1	1	0	1	1	0	1	1/0
CDCEx949	1	1	0	1	1	0	0	1/0

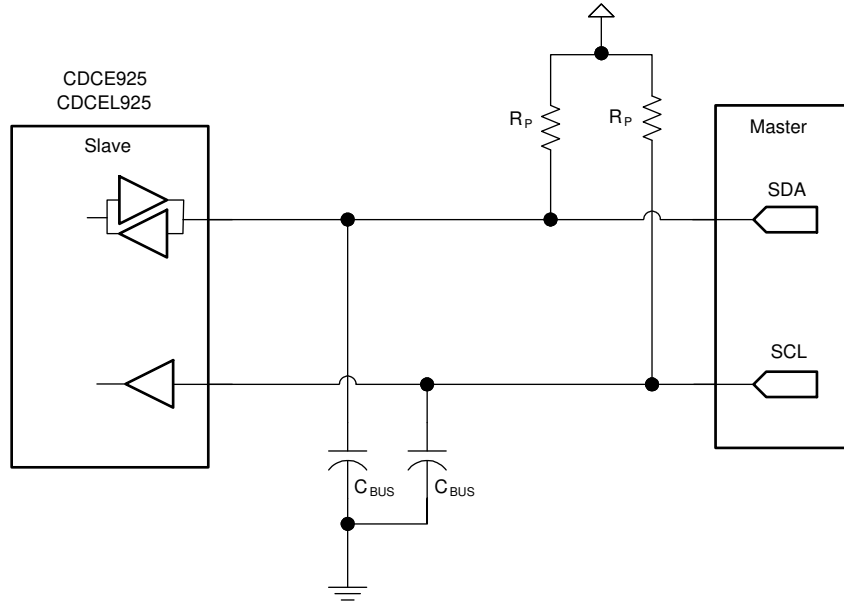
(1) Address bits A0 and A1 are programmable through the SDA/SCL bus (byte 01, bit [1:0]). This allows addressing up to four devices connected to the same SDA/SCL bus. The least-significant bit of the address byte designates a write or read operation.

7.4 Device Functional Modes

7.4.1 SDA/SCL Hardware Interface

[Figure 7-4](#) shows how the CDCEx925 clock synthesizer is connected to the SDA/SCL serial interface bus. Multiple devices can be connected to the bus, but the speed may need to be reduced (400kHz is the maximum) if many devices are connected.

The pullup resistors (R_P) depend on the supply voltage, bus capacitance, and number of connected devices. The recommended pullup value is 4.7k Ω . It must meet the minimum sink current of 3mA at $V_{OLmax} = 0.4V$ for the output stages (for more details, see [SMBus](#) or [I²C Bus](#) specification).



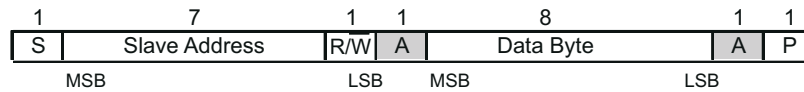
Copyright © 2016, Texas Instruments Incorporated

Figure 7-4. SDA/SCL Hardware Interface

7.5 Programming

Table 7-6. Command Code Definition

BIT	DESCRIPTION
7	0 = <i>Block Read</i> or <i>Block Write</i> operation 1 = <i>Byte Read</i> or <i>Byte Write</i> operation
(6:0)	Byte offset for <i>Byte Read</i> , <i>Block Read</i> , <i>Byte Write</i> and <i>Block Write</i> operations.



S Start Condition

Sr Repeated Start Condition

R/W 1 = Read (Rd) From CDCE9xx Device; 0 = Write (Wr) to CDCE9xxx

A Acknowledge (ACK = 0 and NACK = 1)

P Stop Condition

 Master-to-Slave Transmission

 Slave-to-Master Transmission

Figure 7-5. Generic Programming Sequence



Figure 7-6. Byte Write Protocol

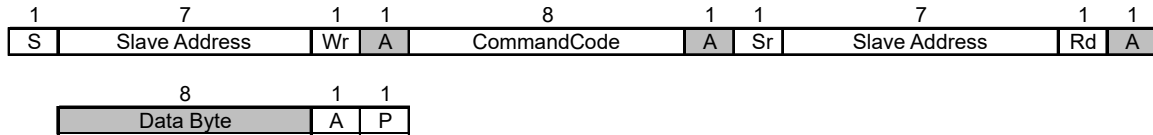
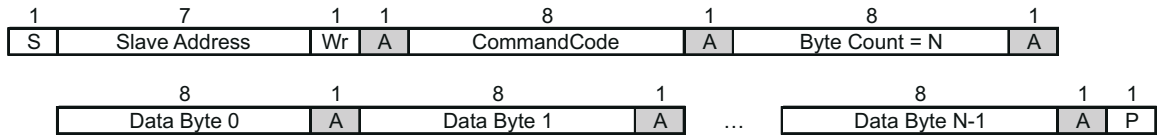


Figure 7-7. Byte Read Protocol



Data byte 0 bits [7:0] is reserved for Revision Code and Vendor Identification. Also, it is used for internal test purpose and must not be overwritten.

Figure 7-8. Block Write Protocol

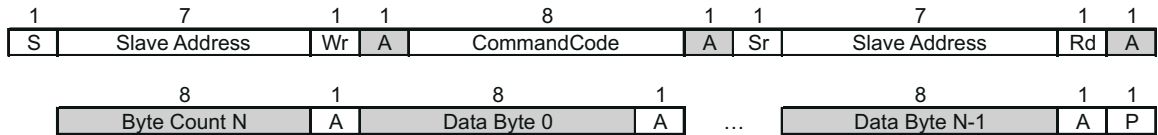


Figure 7-9. Block Read Protocol

8 Register Maps

8.1 SDA/SCL Configuration Registers

The clock input, control pins, PLLs, and output stages are user configurable. The following tables and explanations describe the programmable functions of the CDCE925. All settings can be manually written into the device through the SDA/SCL bus or easily programmed by using the TI Pro-Clock software. TI Pro-Clock software allows the user to quickly make all settings and automatically calculates the values for optimized performance at lowest jitter.

Table 8-1. SDA/SCL Registers

ADDRESS OFFSET	REGISTER DESCRIPTION	TABLE
00h	Generic configuration register	Table 8-3
10h	PLL1 configuration register	Table 8-4
20h	PLL2 configuration register	Table 8-5

The grey-highlighted bits, described in the Configuration Registers tables in the following pages, belong to the Control Terminal register. The user can predefine up to eight different control settings. These settings then can be selected by the external control pins, S0, S1, and S2 (see [Control Terminal Setting](#)).

Table 8-2. Configuration Register, External Control Terminals

	EXTERNAL CONTROL PINS			Y1	PLL1 SETTINGS			PLL2 SETTINGS		
				OUTPUT SELECTION	FREQUENCY SELECTION	SSC SELECTION	OUTPUT SELECTION	FREQUENCY SELECTION	SSC SELECTION	OUTPUT SELECTION
	S2	S1	S0	Y1	FS1	SSC1	Y2Y3	FS2	SSC2	Y4Y5
0	0	0	0	Y1_0	FS1_0	SSC1_0	Y2Y3_0	FS2_0	SSC2_0	Y4Y5_0
1	0	0	1	Y1_1	FS1_1	SSC1_1	Y2Y3_1	FS2_1	SSC2_1	Y4Y5_1
2	0	1	0	Y1_2	FS1_2	SSC1_2	Y2Y3_2	FS2_2	SSC2_2	Y4Y5_2
3	0	1	1	Y1_3	FS1_3	SSC1_3	Y2Y3_3	FS2_3	SSC2_3	Y4Y5_3
4	1	0	0	Y1_4	FS1_4	SSC1_4	Y2Y3_4	FS2_4	SSC2_4	Y4Y5_4
5	1	0	1	Y1_5	FS1_5	SSC1_5	Y2Y3_5	FS2_5	SSC2_5	Y4Y5_5
6	1	1	0	Y1_6	FS1_6	SSC1_6	Y2Y3_6	FS2_6	SSC2_6	Y4Y5_6
7	1	1	1	Y1_7	FS1_7	SSC1_7	Y2Y3_7	FS2_7	SSC2_7	Y4Y5_7
Address offset ⁽¹⁾				04h	13h	10h–12h	15h	23h	20h–22h	25h

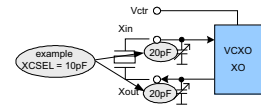
(1) Address offset refers to the byte address in the configuration register in [Table 8-3](#), [Table 8-4](#), and [Table 8-5](#).

Table 8-3. Generic Configuration Register

OFFSET ⁽¹⁾	BIT ⁽²⁾	ACRONYM	DEFAULT ⁽³⁾	DESCRIPTION
00h	7	E_EL	Xb	Device identification (read-only): 1 is CDCE925 (3.3 V out), 0 is CDCEL925 (1.8 V out)
	6:4	RID	Xb	Revision identification number (read-only)
	3:0	VID	1h	Vendor identification number (read-only)
01h	7	–	0b	Reserved – always write 0
	6	EEPIP	0b	EEPROM programming Status ⁽⁴⁾ (read-only) 0 – EEPROM programming is completed 1 – EEPROM is in programming mode
	5	EELock	0b	Permanently lock EEPROM data ⁽⁵⁾ 0 – EEPROM is not locked 1 – EEPROM is permanently locked
	4	PWDN	0b	Device power down (overwrites S0/S1/S2 setting; configuration register settings are unchanged) Note: PWDN cannot be set to 1 in the EEPROM. 0 – Device active (all PLLs and all outputs are enabled) 1 – Device power down (all PLLs in power down and all outputs in high-impedance state)
	3:2	INCLK	00b	Input clock selection: 00 – Xtal 01 – VCXO 10 – LVCMOS 1 – Reserved
	1:0	SLAVE_ADR	00b	Address bits A0 and A1 of the slave receiver address

Table 8-3. Generic Configuration Register (continued)

OFFSET ⁽¹⁾	BIT ⁽²⁾	ACRONYM	DEFAULT ⁽³⁾	DESCRIPTION
02h	7	M1	1b	Clock source selection for output Y1: 0 – Input clock 1 – PLL1 clock
	6	SPICON	0b	Operation mode selection for pins 14/15 ⁽⁶⁾ 0 – Serial programming interface SDA (pin 15) and SCL (pin 14) 1 – Control pins S1 (pin 15) and S2 (pin 14)
	5:4	Y1_ST1	11b	Y1-State0/1 definition 00 – Device power down (all PLLs in power down and all outputs in high-impedance state) 01 – Y1 disabled to high-impedance state 10 – Y1 disabled to low 11 – Y1 enabled
	3:2	Y1_ST0	01b	
	1:0	Pdiv1 [9:8]	001h	
03h	7:0	Pdiv1 [7:0]		10-bit Y1-Output-Divider Pdiv1: 0 – Divider is reset and in standby 1 to 1023 – Divider value
04h	7	Y1_7	0b	Y1_ST0/Y1_ST1 State Selection ⁽⁷⁾ 0 – State0 (predefined by Y1_ST0) 1 – State1 (predefined by Y1_ST1)
	6	Y1_6	0b	
	5	Y1_6	0b	
	4	Y1_6	0b	
	3	Y1_6	0b	
	2	Y1_6	0b	
	1	Y1_6	0b	
	0	Y1_6	0b	
05h	7:3	XCSEL	0Ah	Crystal load-capacitor selection ⁽⁸⁾ 00h – 0 pF 01h – 1 pF 02h – 2 pF : 14h to 1Fh – 20 pF
	2:0		0b	Reserved – do not write other than 0.
06h	7:1	BCOUNT	30h	7-bit byte count (defines the number of bytes which is sent from this device at the next <i>Block Read</i> transfer); all bytes must be read out to correctly finish the read cycle.
	0	EEWRITE	0b	Initiate EEPROM write cycle ⁽⁹⁾ 0 – No EEPROM write cycle 1 – Start EEPROM write cycle (internal registers are saved to the EEPROM)
07h-0Fh		—	0h	Reserved – do not write other than 0



- (1) Writing data beyond 30h may affect device function.
- (2) All data transferred with the MSB first
- (3) Unless customer-specific setting
- (4) During EEPROM programming, no data is allowed to be sent to the device through the SDA/SCL bus until the programming sequence is completed. Data, however, can be read out during the programming sequence (*Byte Read* or *Block Read*).
- (5) If this bit is set to high in the EEPROM, the actual data in the EEPROM is permanently locked. No further programming is possible. Data, however can still be written through the SDA/SCL bus to the internal register to change device function on the fly. But new data can no longer be saved to the EEPROM. EELOCK is effective only if written into the EEPROM.
- (6) Selection of *control pins* is effective only if written into the EEPROM. Once written into the EEPROM, the serial programming pins are no longer available. However, if V_{DDOUT} is forced to GND, the two control pins, S1 and S2, temporarily act as serial programming pins (SDA/SCL), and the two slave receiver address bits are reset to A0 = 0 and A1 = 0.
- (7) These are the bits of the control terminal register. The user can predefine up to eight different control settings. These settings then can be selected by the external control pins, S0, S1, and S2.
- (8) The internal load capacitor (C1, C2) must be used to achieve the best clock performance. External capacitors must be used only to finely adjust C_L by a few picofarads. The value of C_L can be programmed with a resolution of 1 pF for a crystal load range of 0 pF to 20 pF. For CL > 20 pF, use additional external capacitors. Also, the value of the device input capacitance has to be considered which always adds 1.5 pF (6 pF/2 pF) to the selected C_L. For more information about VCXO configuration and crystal recommendation, see [VCXO Application Guideline for CDCE\(L\)9xx Family](#) (SCAA085).
- (9) Note: The EEPROM WRITE bit must be sent last. This ensures that the content of all internal registers are stored in the EEPROM. The EEWRITE cycle is initiated with the rising edge of the EEWRITE bit. A static level-high does not trigger an EEPROM WRITE cycle. The EEWRITE bit must be reset to low after the programming is completed. The programming status can be monitored by reading out EEPIP. If EELOCK is set to high, no EEPROM programming is possible.

Table 8-4. PLL1 Configuration Register

OFFSET ⁽¹⁾	BIT ⁽²⁾	ACRONYM	DEFAULT ⁽³⁾	DESCRIPTION
10h	7:5	SSC1_7 [2:0]	000b	SSC1: PLL1 SSC selection (modulation amount). ⁽⁴⁾ Down 000 (Off) 001 – 0.25% 010 – 0.5% 011 – 0.75% 100 – 1.0% 101 – 1.25% 110 – 1.5% 111 – 2.0% Center 000 (Off) 001 ± 0.25% 010 ± 0.5% 011 ± 0.75% 100 ± 1.0% 101 ± 1.25% 110 ± 1.5% 111 ± 2.0%
	4:2	SSC1_6 [2:0]	000b	
	1:0	SSC1_5 [2:1]	000b	
11h	7	SSC1_5 [0]	000b	
	6:4	SSC1_4 [2:0]		
	3:1	SSC1_3 [2:0]		
	0	SSC1_2 [2]		
12h	7:6	SSC1_2 [1:0]	000b	
	5:3	SSC1_1 [2:0]		
	2:0	SSC1_0 [2:0]		
13h	7	FS1_7	0b	FS1_x: PLL1 frequency selection ⁽⁴⁾ 0 – f_{VCO1_0} (predefined by PLL1_0 – multiplier/divider value) 1 – f_{VCO1_1} (predefined by PLL1_1 – multiplier/divider value)
	6	FS1_6	0b	
	5	FS1_5	0b	
	4	FS1_4	0b	
	3	FS1_3	0b	
	2	FS1_2	0b	
	1	FS1_1	0b	
	0	FS1_0	0b	
14h	7	MUX1	1b	PLL1 multiplexer: 0 – PLL1 1 – PLL1 bypass (PLL1 is in power down)
	6	M2	1b	Output Y2 multiplexer: 0 – Pdiv1 1 – Pdiv2
	5:4	M3	10b	Output Y3 multiplexer: 00 – Pdiv1-divider 01 – Pdiv2-divider 10 – Pdiv3-divider 11 – Reserved
	3:2	Y2Y3_ST1	11b	Y2, Y3-state0/1definition: 00 – Y2/Y3 disabled to high-impedance state (PLL1 is in power down) 01 – Y2/Y3 disabled to high-impedance state (PLL1 on) 10 – Y2/Y3 disabled to low (PLL1 on) 11 – Y2/Y3 enabled (normal operation, PLL1 on)
	1:0	Y2Y3_ST0	01b	
15h	7	Y2Y3_7	0b	Y2Y3_x output state selection ⁽⁴⁾ 0 – state0 (predefined by Y2Y3_ST0) 1 – state1 (predefined by Y2Y3_ST1)
	6	Y2Y3_6	0b	
	5	Y2Y3_5	0b	
	4	Y2Y3_4	0b	
	3	Y2Y3_3	0b	
	2	Y2Y3_2	0b	
	1	Y2Y3_1	1b	
	0	Y2Y3_0	0b	
16h	7	SSC1DC	0b	PLL1 SSC down/center selection: 0 – Down 1 – Center
	6:0	Pdiv2	01h	7-bit Y2-output-divider Pdiv2: 0 – Reset and in standby 1 to 127 – Divider value
17h	7	—	0b	Reserved – do not write others than 0
	6:0	Pdiv3	01h	7-bit Y3-output-divider Pdiv3: 0 – Reset and in standby 1 to 127 – Divider value

Table 8-4. PLL1 Configuration Register (continued)

OFFSET ⁽¹⁾	BIT ⁽²⁾	ACRONYM	DEFAULT ⁽³⁾	DESCRIPTION	
18h	7:0	PLL1_0N [11:4]	004h	PLL1_0 ⁽⁵⁾ : 30-bit multiplier/divider value for frequency f_{VCO1_0} (for more information, see PLL Frequency Planning).	
19h	7:4	PLL1_0N [3:0]			
	3:0	PLL1_0R [8:5]	000h		
1Ah	7:3	PLL1_0R[4:0]	10h		
	2:0	PLL1_0Q [5:3]			
1Bh	7:5	PLL1_0Q [2:0]	010b		
	4:2	PLL1_0P [2:0]			
	1:0	VCO1_0_RANGE			00b
1Ch	7:0	PLL1_1N [11:4]	004h		PLL1_1 ⁽⁵⁾ : 30-bit multiplier/divider value for frequency f_{VCO1_1} (for more information, see PLL Frequency Planning).
1Dh	7:4	PLL1_1N [3:0]			
	3:0	PLL1_1R [8:5]	000h		
1Eh	7:3	PLL1_1R[4:0]	10h		
	2:0	PLL1_1Q [5:3]			
1Fh	7:5	PLL1_1Q [2:0]	010b		
	4:2	PLL1_1P [2:0]			
	1:0	VCO1_1_RANGE		00b	

- (1) Writing data beyond 30h may adversely affect device function.
- (2) All data is transferred MSB-first.
- (3) Unless a custom setting is used
- (4) The user can predefine up to eight different control settings. In normal device operation, these settings can be selected by the external control pins, S0, S1, and S2.
- (5) PLL settings limits: $16 \leq q \leq 63$, $0 \leq p \leq 7$, $0 \leq r \leq 511$, $0 < N < 4096$

Table 8-5. PLL2 Configuration Register

OFFSET ⁽¹⁾	BIT ⁽²⁾	ACRONYM	DEFAULT ⁽³⁾	DESCRIPTION
20h	7:5	SSC2_7 [2:0]	000b	SSC2: PLL2 SSC selection (modulation amount). ⁽⁴⁾
	4:2	SSC2_6 [2:0]	000b	
	1:0	SSC2_5 [2:1]	000b	
21h	7	SSC2_5 [0]	000b	
	6:4	SSC2_4 [2:0]		
	3:1	SSC2_3 [2:0]		
	0	SSC2_2 [2]		
22h	7:6	SSC2_2 [1:0]	000b	
	5:3	SSC2_1 [2:0]		
	2:0	SSC2_0 [2:0]		
23h	7	FS2_7	0b	FS2_x: PLL2 frequency selection ⁽⁴⁾ 0 – f_{VCO2_0} (predefined by PLL2_0 – multiplier/divider value) 1 – f_{VCO2_1} (predefined by PLL2_1 – multiplier/divider value)
	6	FS2_6	0b	
	5	FS2_5	0b	
	4	FS2_4	0b	
	3	FS2_3	0b	
	2	FS2_2	0b	
	1	FS2_1	0b	
	0	FS2_0	0b	

Table 8-5. PLL2 Configuration Register (continued)

OFFSET ⁽¹⁾	BIT ⁽²⁾	ACRONYM	DEFAULT ⁽³⁾	DESCRIPTION
24h	7	MUX2	1b	PLL2 multiplexer: 0 – PLL2 1 – PLL2 bypass (PLL2 is in power down)
	6	M4	1b	Output Y4 multiplexer: 0 – Pdiv2 1 – Pdiv4
	5:4	M5	10b	Output Y5 multiplexer: 00 – Pdiv2-divider 01 – Pdiv4-divider 10 – Pdiv5-divider 11 – Reserved
	3:2	Y4Y5_ST1	11b	Y4, Y5-State0/1definition: 00 – Y4/Y5 disabled to high-impedance state (PLL2 is in power down) 01 – Y4/Y5 disabled to high-impedance state (PLL2 on) 10 – Y4/Y5 disabled to low (PLL2 on) 11 – Y4/Y5 enabled (normal operation, PLL2 on)
	1:0	Y4Y5_ST0	01b	
25h	7	Y4Y5_7	0b	Y4Y5_x output state selection ⁽⁴⁾ 0 – state0 (predefined by Y4Y5_ST0) 1 – state1 (predefined by Y4Y5_ST1)
	6	Y4Y5_6	0b	
	5	Y4Y5_5	0b	
	4	Y4Y5_4	0b	
	3	Y4Y5_3	0b	
	2	Y4Y5_2	0b	
	1	Y4Y5_1	1b	
	0	Y4Y5_0	0b	
26h	7	SSC2DC	0b	PLL2 SSC down/center selection: 0 – Down 1 – Center
	6:0	Pdiv4	01h	7-Bit Y4-output-divider Pdiv4: 0 – Reset and in standby 1 to 127 – Divider value
27h	7	—	0b	Reserved – do not write others than 0
	6:0	Pdiv5	01h	7-bit Y5-output-divider Pdiv5: 0 – Reset and in standby 1 to 127 – Divider value
28h	7:0	PLL2_0N [11:4]	004h	PLL2_0 ⁽⁵⁾ : 30-Bit Multiplier/Divider value for frequency f_{VCO2_0} (for more information, see PLL Frequency Planning).
29h	7:4	PLL2_0N [3:0]		
	3:0	PLL2_0R [8:5]		
2Ah	7:3	PLL2_0R[4:0]		
	2:0	PLL2_0Q [5:3]		
2Bh	7:5	PLL2_0Q [2:0]	010b	f_{VCO2_0} range selection: 00 – $f_{VCO2_0} < 125$ MHz 01 – $125 \text{ MHz} \leq f_{VCO2_0} < 150$ MHz 10 – $150 \text{ MHz} \leq f_{VCO2_0} < 175$ MHz 11 – $f_{VCO2_0} \geq 175$ MHz
	4:2	PLL2_0P [2:0]		
	1:0	VCO2_0_RANGE	00b	
2Ch	7:0	PLL2_1N [11:4]	004h	PLL2_1 ⁽⁵⁾ : 30-bit multiplier/divider value for frequency f_{VCO2_1} (for more information, see PLL Frequency Planning).
2Dh	7:4	PLL2_1N [3:0]		
	3:0	PLL2_1R [8:5]		
2Eh	7:3	PLL2_1R[4:0]		
	2:0	PLL2_1Q [5:3]		
2Fh	7:5	PLL2_1Q [2:0]	010b	f_{VCO2_1} range selection: 00 – $f_{VCO2_1} < 125$ MHz 01 – $125 \text{ MHz} \leq f_{VCO2_1} < 150$ MHz 10 – $150 \text{ MHz} \leq f_{VCO2_1} < 175$ MHz 11 – $f_{VCO2_1} \geq 175$ MHz
	4:2	PLL2_1P [2:0]		
	1:0	VCO2_1_RANGE	00b	

(1) Writing data beyond 30h may adversely affect device function.

(2) All data is transferred MSB-first.

(3) Unless a custom setting is used

(4) The user can predefine up to eight different control settings. In normal device operation, these settings can be selected by the external control pins, S0, S1, and S2.

(5) PLL settings limits: $16 \leq q \leq 63$, $0 \leq p \leq 7$, $0 \leq r \leq 511$, $0 < N < 4096$

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The CDCEx925 device is an easy-to-use high-performance, programmable CMOS clock synthesizer that can be used as a crystal buffer or clock synthesizer with separate output supply pin. The CDCEx925 features an on-chip loop filter and Spread-spectrum modulation. Programming can be done through SPI, pin-mode, or using on-chip EEPROM. This section shows some examples of using CDCEx925 in various applications.

9.2 Typical Application

Figure 9-1 shows the use of the CDCEx925 devices for replacement of crystals and crystal oscillators on a Gigabit Ethernet Switch application.

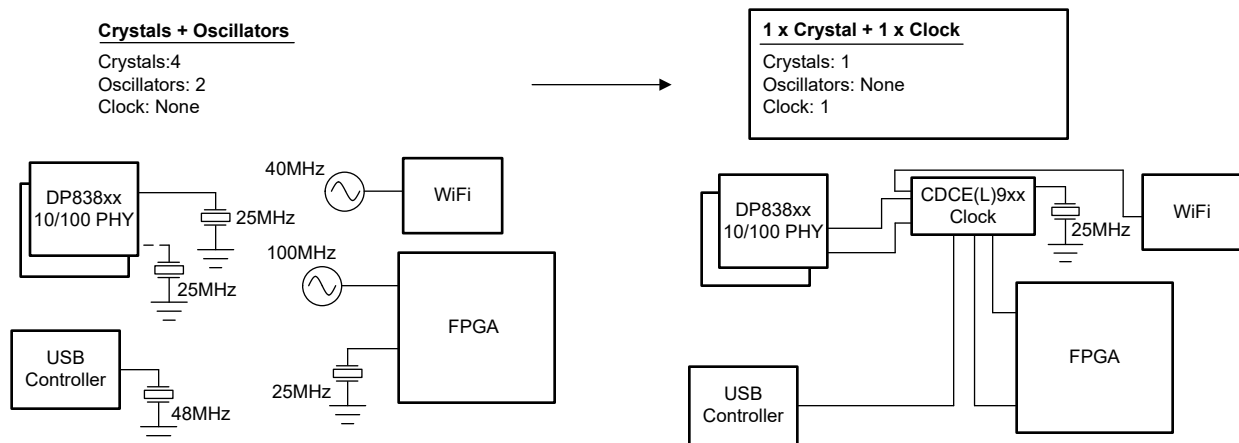


Figure 9-1. Crystal and Oscillator Replacement Example

9.2.1 Design Requirements

CDCEx925 supports spread spectrum clocking (SSC) with multiple control parameters:

- Modulation amount (%)
- Modulation frequency (>20kHz)
- Modulation shape (triangular)
- Center spread / down spread (\pm or $-$)

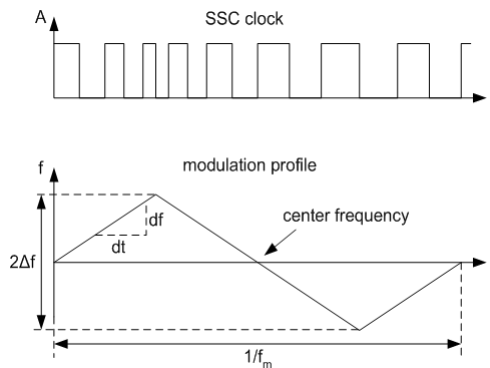
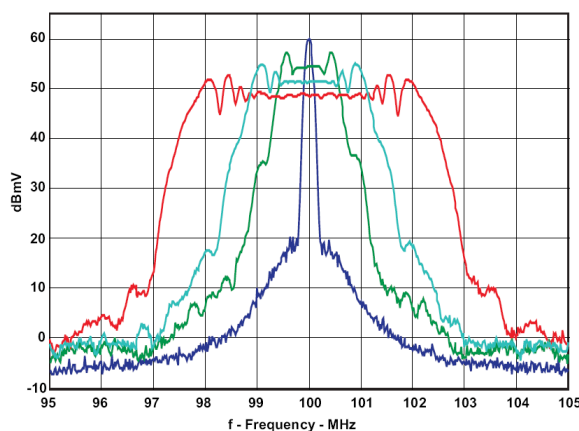


Figure 9-2. Modulation Frequency (fm) and Modulation Amount

9.2.2 Detailed Design Procedure

9.2.2.1 Spread-Spectrum Clock (SSC)

Spread-spectrum modulation is a method to spread emitted energy over a larger bandwidth. In clocking, spread-spectrum can reduce electromagnetic interference (EMI) by reducing the level of emission from clock distribution network.



CDCS502 with a 25MHz Crystal, FS = 1, $f_{OUT} = 100\text{MHz}$, and 0%, ± 0.5 , $\pm 1\%$, and $\pm 2\%$ SSC

Figure 9-3. Comparison Between Typical Clock Power Spectrum and Spread-Spectrum Clock

9.2.2.2 PLL Frequency Planning

At a given input frequency (f_{IN}), the output frequency (f_{OUT}) of the CDCE925 is calculated with [Equation 1](#).

$$f_{OUT} = \frac{f_{IN}}{P_{div}} \times \frac{N}{M} \quad (1)$$

where

- M (1 to 511) and N (1 to 4095) are the multiplier/divide values of the PLL
- Pdiv (1 to 127) is the output divider

The target VCO frequency (f_{VCO}) of each PLL is calculated with [Equation 2](#).

$$f_{VCO} = f_{IN} \times \frac{N}{M} \quad (2)$$

The PLL internally operates as fractional divider and needs the following multiplier/divider settings:

$$NP = 4 - \text{int}(\log_2 \frac{N}{M}) \quad [\text{if } P < 0 \text{ then } P = 0] \quad Q = \text{int}(\frac{N'}{M}) \quad R = N' - M \times Q \quad (3)$$

where

- $N' = N \times 2^P$
- $N \geq M$
- $80\text{MHz} \leq f_{VCO} \leq 230\text{MHz}$
- $16 \leq q \leq 63$
- $0 \leq p \leq 4$
- $0 \leq r \leq 11$

Example:

for $f_{IN} = 27\text{MHz}$; $M = 1$; $N = 4$; $P_{div} = 2$;

- $f_{OUT} = 54\text{MHz}$
- $f_{VCO} = 108\text{MHz}$
- $P = 4 - \text{int}(\log_2 4) = 4 - 2 = 2$
- $N'' = 4 \times 2^2 = 16$
- $Q = \text{int}(16) = 16$
- $R = 16 - 16 = 0$

for $f_{IN} = 27\text{MHz}$; $M = 2$; $N = 11$; $P_{div} = 2$;

- $f_{OUT} = 74.25\text{MHz}$
- $f_{VCO} = 148.50\text{MHz}$
- $P = 4 - \text{int}(\log_2 5.5) = 4 - 2 = 2$
- $N'' = 11 \times 2^2 = 44$
- $Q = \text{int}(22) = 22$
- $R = 44 - 44 = 0$

The values for P, Q, R, and N' are automatically calculated when using TI Pro-Clock software.

9.2.2.3 Crystal Oscillator Start-Up

When the CDCE925 is used as a crystal buffer, crystal oscillator start-up dominates the start-up time compared to the internal PLL lock time. Figure 9-4 shows the oscillator start-up sequence for a 27MHz crystal input with an 8pF load. The start-up time for the crystal is in the order of approximately 250µs, compared to approximately 10µs of lock time. In general, lock time is an order of magnitude less compared to the crystal start-up time.

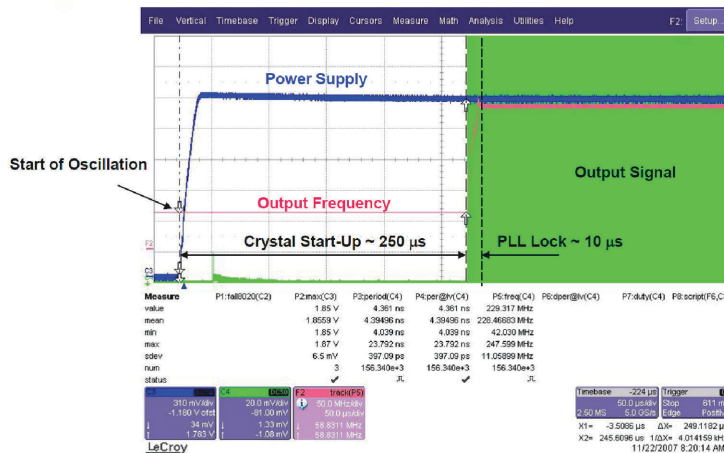
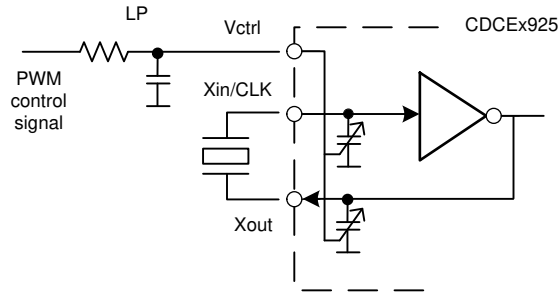


Figure 9-4. Crystal Oscillator Start-Up vs PLL Lock Time

9.2.2.4 Frequency Adjustment With Crystal Oscillator Pulling

The frequency for the CDCE925 is adjusted for media and other applications with the VCXO control input V_{Ctrl} . If a PWM-modulated signal is used as a control signal for the VCXO, an external filter is needed.



Copyright © 2016, Texas Instruments Incorporated

Figure 9-5. Frequency Adjustment Using PWM Input to the VCXO Control

9.2.2.5 Unused Inputs and Outputs

If VCXO pulling functionality is not required, V_{Ctrl} should be left floating. All other unused inputs should be set to GND. Unused outputs should be left floating.

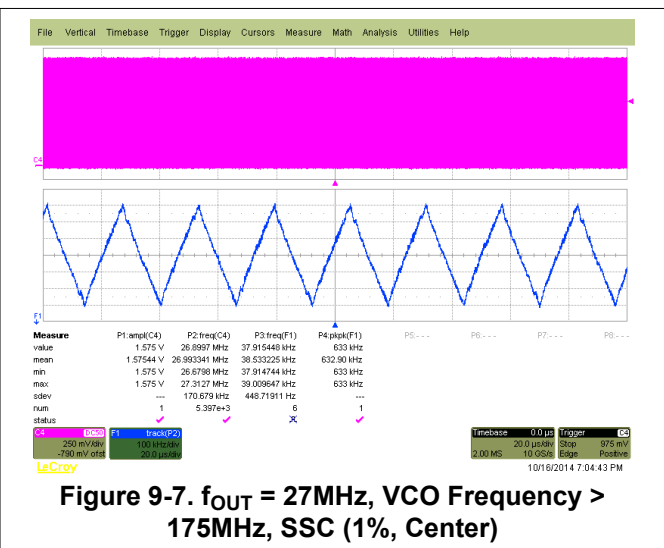
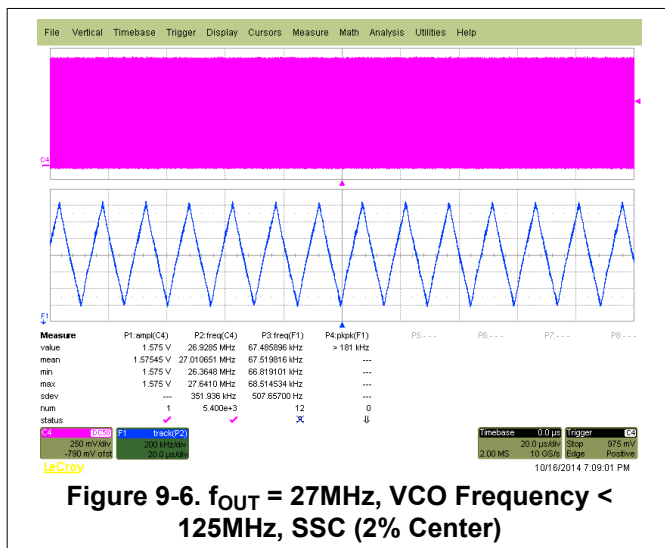
If one output block is not used, TI recommends disabling it. However, TI always recommends providing the supply for the second output block even if it is disabled.

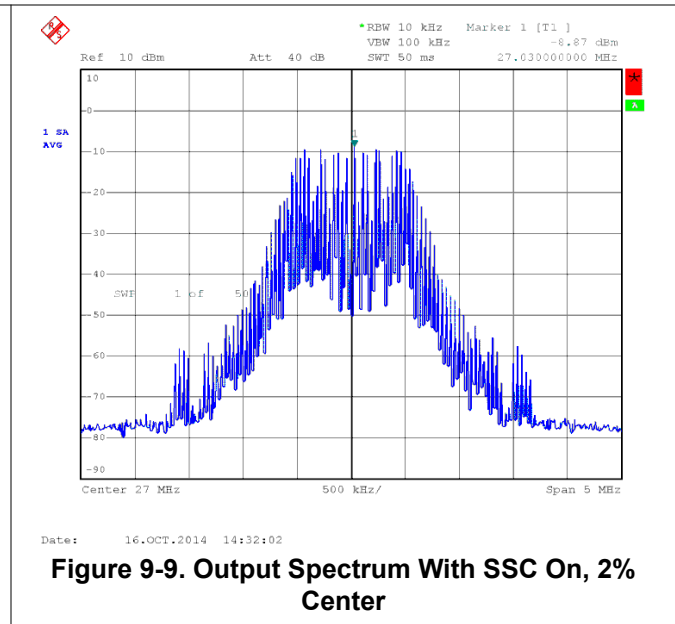
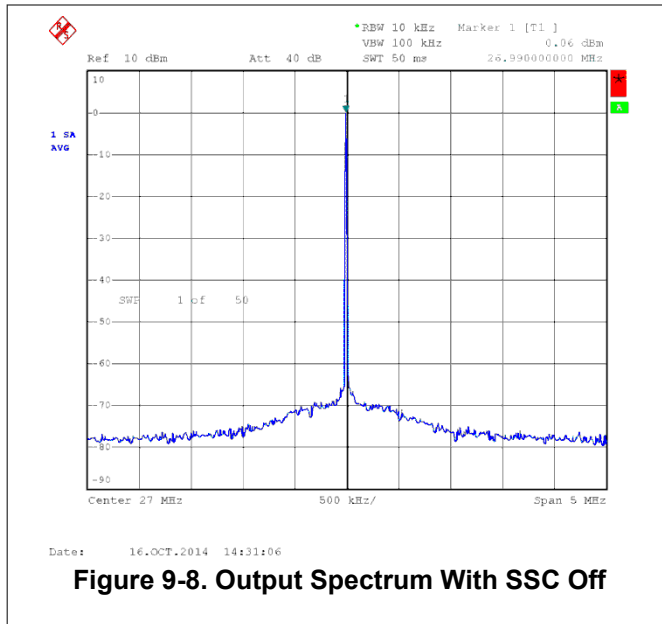
9.2.2.6 Switching Between XO and VCXO Mode

When the CDCE925 is in crystal oscillator or in VCXO configuration, the internal capacitors require different internal capacitance. The following steps are recommended to switch to VCXO mode when the configuration for the on-chip capacitor is still set for XO mode. To center the output frequency to 0 ppm:

1. While in XO mode, put $V_{Ctrl} = V_{dd}/2$
2. Switch from XO mode to VCXO mode
3. Program the internal capacitors to obtain 0 ppm at the output.

Figure 9-6, Figure 9-7, Figure 9-8, and Figure 9-9 show CDCE925 measurements with the SSC feature enabled. The device is configured with a 27MHz input and a 27MHz output.





9.3 Power Supply Recommendations

When using an external reference clock, XIN/CLK must be driven before V_{DD} ramps to avoid risk of unstable output. If V_{DDOUT} is applied before V_{DD} , TI recommends keeping V_{DD} pulled to GND until V_{DDOUT} is ramped. If the V_{DDOUT} is powered while V_{DD} is floating, there is a risk of high current flowing on the V_{DDOUT} .

The device has a power-up control connected to the 1.8V supply. This disables the device until the 1.8V supply reaches a sufficient voltage level. Then, the device switches on all internal components, including the outputs. If there is a 3.3V V_{DDOUT} available before the 1.8V, the outputs stay disabled until the 1.8V supply reaches a certain level.

9.4 Layout

9.4.1 Layout Guidelines

When the CDCEX937 is used as a crystal buffer, any parasitics across the crystal affects the pulling range of the VCXO. Therefore, take care in placing the crystal units on the board. Crystals must be placed as close to the device as possible, ensuring that the routing lines from the crystal terminals to XIN and XOUT have the same length.

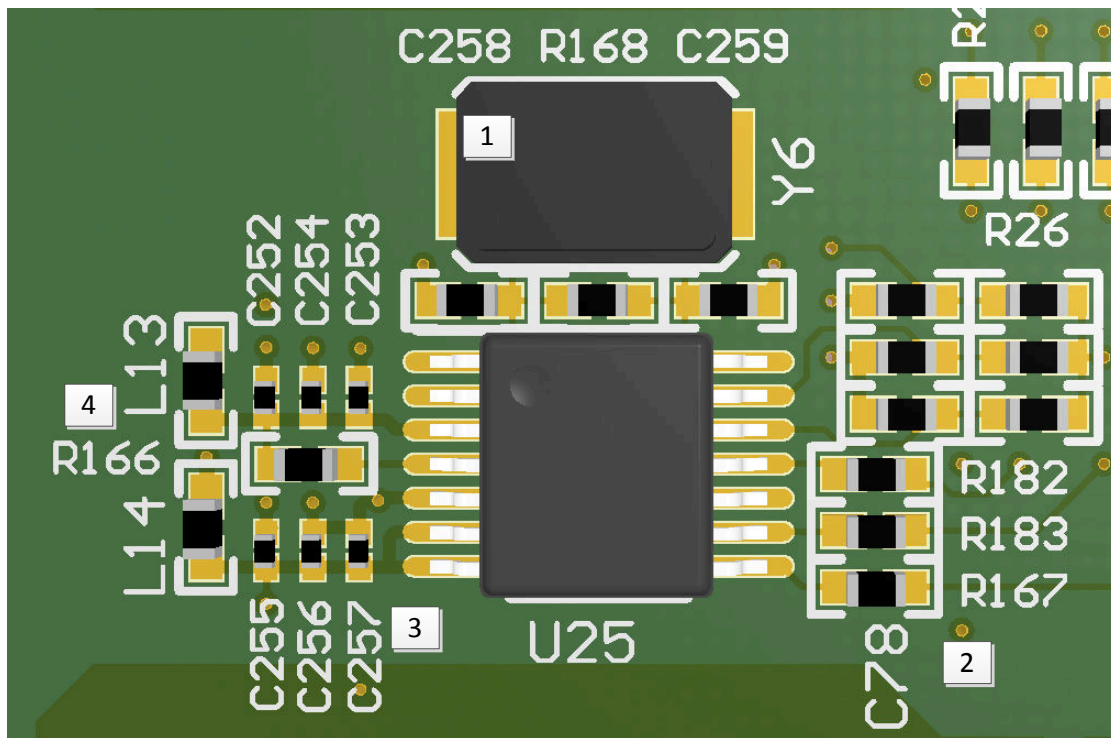
If possible, cut out both ground plane and power plane under the area where the crystal and the routing to the device are placed. In this area, always avoid routing any other signal line, as it could be a source of noise coupling.

Additional discrete capacitors can be required to meet the load capacitance specification of certain crystal. For example, a 10.7pF load capacitor is not fully programmable on the chip, because the internal capacitor can range from 0pF to 20pF with steps of 1pF. The 0.7pF capacitor therefore can be discretely added on top of an internal 10pF capacitor.

To minimize the inductive influence of the trace, TI recommends placing this small capacitor as close to the device as possible, and symmetrically with respect to XIN and XOUT.

Figure 9-10 shows a conceptual layout detailing recommended placement of power supply bypass capacitors on the basis of CDCEX937. For component side mounting, use 0402 body size capacitors to facilitate signal routing. Keep the connections between the bypass capacitors and the power supply on the device as short as possible. Ground the other side of the capacitor using a low-impedance connection to the ground plane.

9.4.2 Layout Example



- | | | | |
|---|---|---|---|
| 1 | Place crystal with associated load caps as close to the chip | 2 | Place series termination resistors at Clock outputs to improve signal integrity |
| 3 | Place bypass caps close to the device pins, ensure wide freq. range | 4 | Use ferrite beads to isolate the device supply pins from board noise sources |

Figure 9-10. Annotated Layout

1. Place crystal with associated load caps as close to the chip
2. Place series termination resistors at Clock outputs to improve signal integrity
3. Place bypass caps close to the device pins, ensure wide freq. range
4. Use ferrite beads to isolate the device supply pins from board noise sources

10 Device and Documentation Support

10.1 Device Support

10.1.1 Third-Party Products Disclaimer

TI'S PUBLICATION OF INFORMATION REGARDING THIRD-PARTY PRODUCTS OR SERVICES DOES NOT CONSTITUTE AN ENDORSEMENT REGARDING THE SUITABILITY OF SUCH PRODUCTS OR SERVICES OR A WARRANTY, REPRESENTATION OR ENDORSEMENT OF SUCH PRODUCTS OR SERVICES, EITHER ALONE OR IN COMBINATION WITH ANY TI PRODUCT OR SERVICE.

10.1.2 Development Support

For development support see the following:

- [SMBus](#)
- [I²C Bus](#)

10.2 Documentation Support

10.2.1 Related Documentation

For related documentation see the following:

Texas Instruments, [VCXO Application Guideline for CDCE\(L\)9xx Family application note](#)

10.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](#). Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.4 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of Use](#).

10.5 Trademarks

Ethernet™ is a trademark of Xerox Corporation.

DaVinci™, OMAP™, Pro-Clock™, and TI E2E™ are trademarks of Texas Instruments.

Bluetooth® is a registered trademark of Bluetooth SIG, Inc.

All trademarks are the property of their respective owners.

10.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.7 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

11 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision I (October 2016) to Revision J (June 2025)	Page
• Updated the numbering format for tables, figures, and cross-references throughout the document.....	1
• Changed all instances of <i>PLL Multiplier/Divider Definition</i> to <i>PLL Frequency Planning</i>	1
• Changed <i>Data Protocol</i> section.....	15
• Changed <i>Power Supply Recommendations</i> section.....	27

Changes from Revision H (August 2016) to Revision I (October 2016)	Page
• Changed data sheet title from: <i>CDCEx925 Programmable 2-PLL VCXO Clock Synthesizer With 1.8-V, 2.5-V, 3.3-V LVC MOS Outputs</i> to: <i>CDCE(L)925: Flexible Low Power LVC MOS Clock Generator With SSC Support for EMI Reduction</i>	1

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
CDCE925PW	Active	Production	TSSOP (PW) 16	90 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCE925
CDCE925PW.B	Active	Production	TSSOP (PW) 16	90 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCE925
CDCE925PWG4	Active	Production	TSSOP (PW) 16	90 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCE925
CDCE925PWR	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCE925
CDCE925PWR.B	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCE925
CDCE925PWRG4	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCE925
CDCE925PWRG4.B	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCE925
CDCEL925PW	Active	Production	TSSOP (PW) 16	90 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKEL925
CDCEL925PW.B	Active	Production	TSSOP (PW) 16	90 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKEL925
CDCEL925PWR	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKEL925
CDCEL925PWR.B	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKEL925
CDCEL925PWRG4	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKEL925
CDCEL925PWRG4.B	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKEL925

(1) **Status:** For more details on status, see our [product life cycle](#).

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCE925PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CDCE925PWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CDCEL925PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CDCEL925PWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS


*All dimensions are nominal

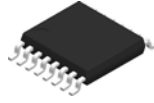
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCE925PWR	TSSOP	PW	16	2000	353.0	353.0	32.0
CDCE925PWRG4	TSSOP	PW	16	2000	353.0	353.0	32.0
CDCEL925PWR	TSSOP	PW	16	2000	353.0	353.0	32.0
CDCEL925PWRG4	TSSOP	PW	16	2000	353.0	353.0	32.0

TUBE


*All dimensions are nominal

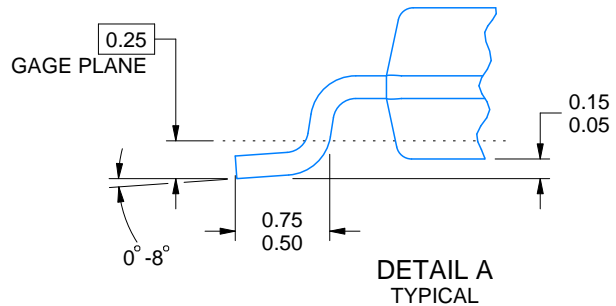
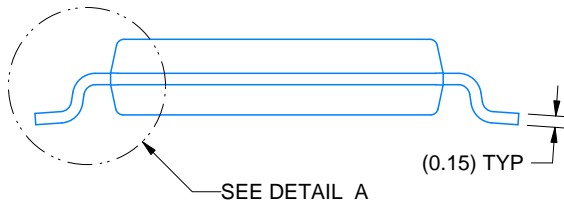
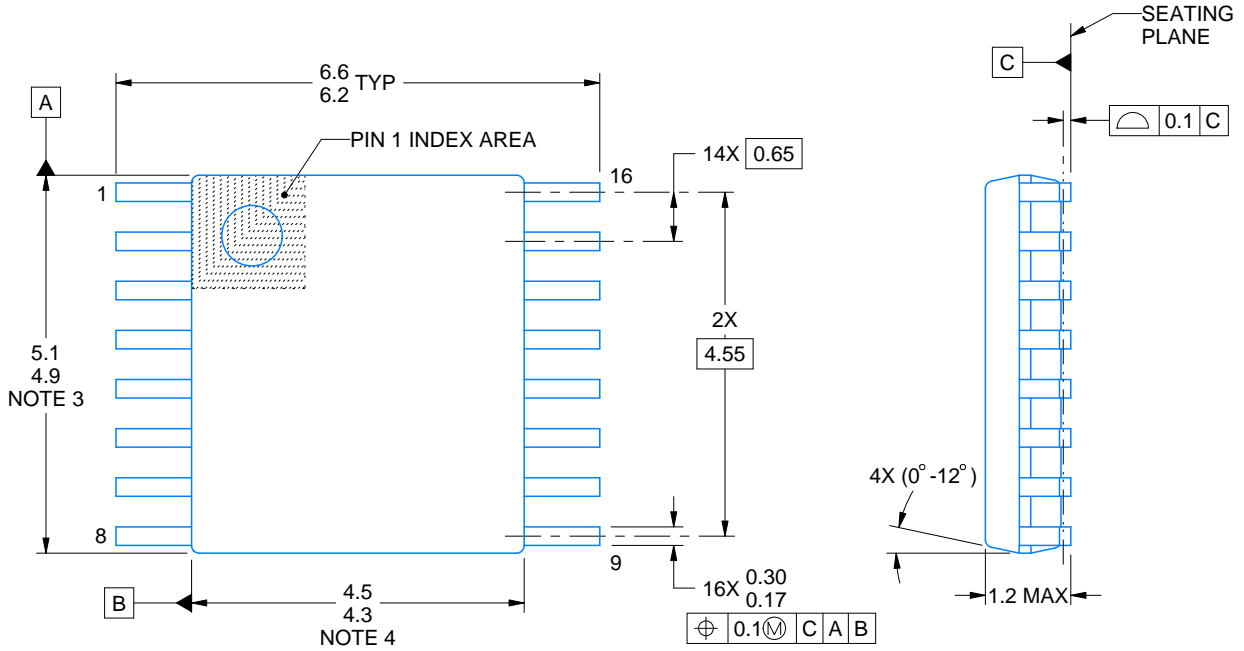
Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
CDCE925PW	PW	TSSOP	16	90	530	10.2	3600	3.5
CDCE925PW.B	PW	TSSOP	16	90	530	10.2	3600	3.5
CDCE925PWG4	PW	TSSOP	16	90	530	10.2	3600	3.5
CDCEL925PW	PW	TSSOP	16	90	530	10.2	3600	3.5
CDCEL925PW.B	PW	TSSOP	16	90	530	10.2	3600	3.5

PW0016A



PACKAGE OUTLINE TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



4220204/B 12/2023

NOTES:

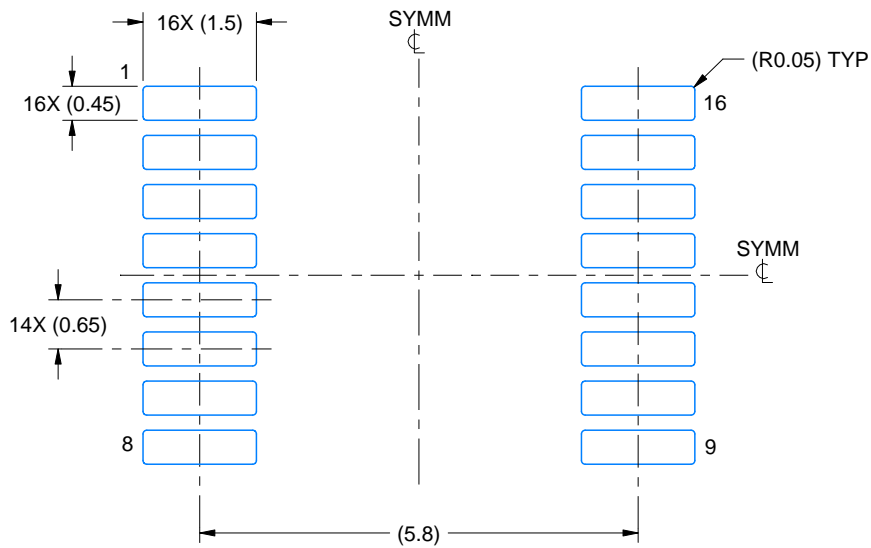
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.

EXAMPLE BOARD LAYOUT

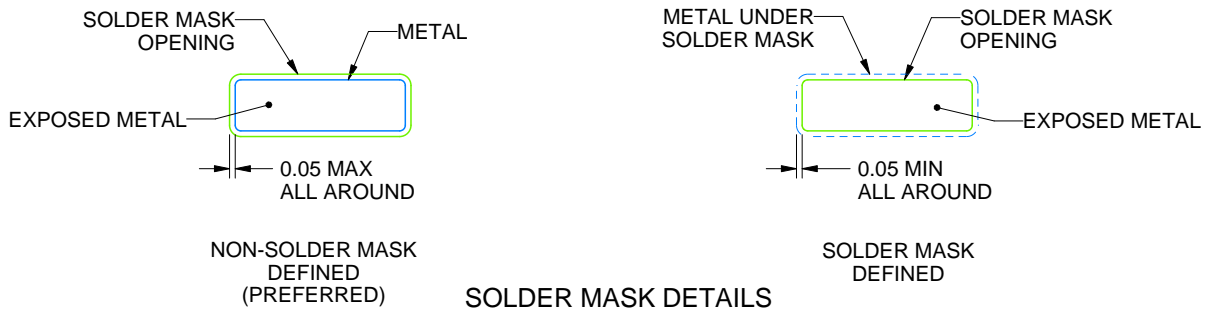
PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X



SOLDER MASK DETAILS

4220204/B 12/2023

NOTES: (continued)

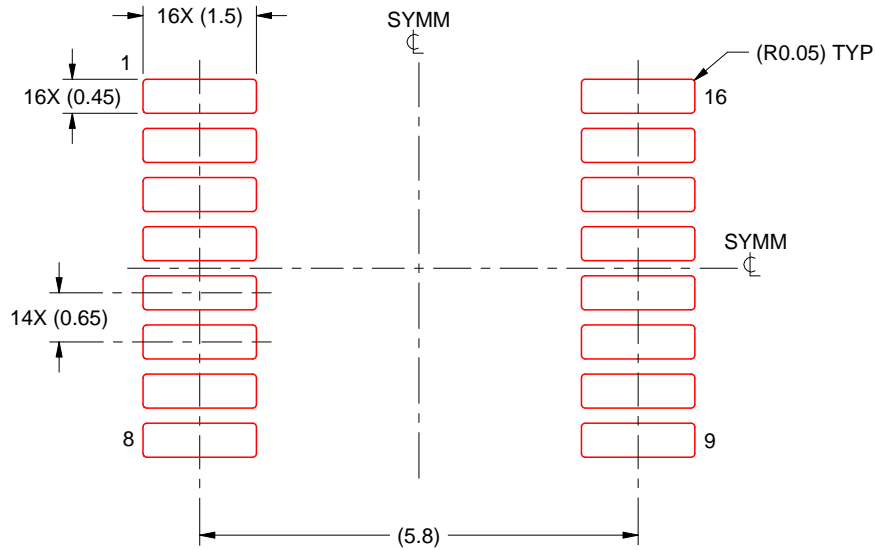
- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220204/B 12/2023

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to [TI's Terms of Sale](#), [TI's General Quality Guidelines](#), or other applicable terms available either on [ti.com](#) or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2025, Texas Instruments Incorporated

Last updated 10/2025